The International Conference on Software Testing, Verification and Validation (ICST) is the premier conference in all areas related to software quality. Software systems present unique engineering challenges to the tester, not least because they can exhibit non-determinism and emergent behaviour. No other engineering artefact is more closely intertwined with the human activity, resulting in complex hybrid systems that involve software, human judgement and, sometimes, political, legal and social processes.

As a result, software verification & validation including testing, inspections, model analysis, safety certification, etc. draws upon a wide spectrum of disciplines, including engineering, mathematics and also psychology. It touches on all aspects of Computer Science and Software Engineering research and impacts on almost every software practitioner. ICST seeks to meet these problems by bringing together researchers and practitioners for a conference that includes all aspects of software testing, as it is most widely construed.

ICST welcomes research papers as well as industrial experience reports from software development and testing practitioners. For the research papers, ICST seeks high quality original work. For the industrial papers ICST seeks papers that present real world experience from which others can benefit.

Authors of best papers from the conference will be invited to submit extended versions of their papers for a special issue of Software Testing, Verification, and Reliability, a Wiley journal.

**Topics of interest include, but are not limited to:**

- Software testing theory and practice
- Model-based testing
- Domain specific testing including, but not limited to, security testing, web services testing, database testing, embedded software testing, and OO software testing
- Verification & validation
- Quality assurance
- Model checking
- Empirical studies
- Metrics
- Fuzz testing
- Inspections
- Tools
- Testability and diagnosability
- Design for testability
- Testing education
- Testing in multidisciplinary applications
- Technology transfer
- Model-driven engineering and testing
- Agile/iterative/incremental testing processes
- Open source software/3rd party software testing
- Novel approaches to software reliability assessment

**Important dates**

- **Papers**
  - Submission of abstracts: September 25, 2010
  - Submission of full papers: October 1, 2010
  - Notification: November 30, 2010
  - Date of conference: March 21-25, 2011

- **Ph. D. Symposium**
  - Same deadlines as for papers

- **Workshops**
  - Submission of proposals: September 3, 2010

---

**Conference Location**

The conference will be held in Hotel Esplanade, an urban oasis of sleek design and intuitive service in the heart of the Berlin’s cultural district.
Program Committee ICST 2011

Giuliano Antoniol, Ecole Polytechnique De Montreal, Canada
Andrea Arcuri, Simula Research Lab, Norway
Paul Baker, Motorola, UK
Klaus Beetz, Siemens, USA
Fevzi Belli, Paderborn University, Germany
Antonia Bertolino, CNR/ISTI, Italy
James Bieman, Colorado State University, USA
Dave Binkley, Loyola College in Maryland, USA
Mario Bravetti, Bologna University, Italy
Renee Bryce, Utah State University, USA
Jeffrey Carver, University of Alabama, USA
Mei-Hwa Chen, State University of New York - Albany, USA
T.Y. Chen, Swinburne University of Technology, Australia
Myra Cohen, University of Nebraska – Lincoln, USA
Juergen Dingel, School of Computing Queen's University, Canada
Hyunsook Do, North Dakota State University, USA
Lydie du Bousquet, Joseph Fourier University, France
Khaled ElFakih, American University of Sharjah, UAE
Robert Feldt, Blekinge Institute of Technology, Sweden
Robert France, Colorado State University, USA
Gordon Fraser, Saarland University, Germany
Angelo Gargantini, University of Bergamo, Italy
Vahid Garousi, University of Calgary, Canada
Wolfgang Grieskamp, Microsoft Research, USA
Roland Groz, LSR-IMAG, France
Yann-Gaël Guéhéneuc, Ecole Polytechnique De Montreal, Canada
Toru Hasegawa, KDDI R&D Labs, Japan
Dieter Hogrefe, Gottingen University, Germany
Gerard Holzmann, NASA/JPL, USA
Florentin Ipaté, University of Pitesti, Romania
Sarfraz Khurshid, University of Texas - Austin, USA
Myungchul Kim, Information and Communications University, Korea
Jens Knoop, Technische Universität Wien, Austria
Pieter Kritzinger, University of Cape Town, South Africa
Yvan Labiche, Carleton University, Canada
Yves Le Traon, Telecom Bretagne, France
Martin Leucker, TU München, Germany
Haretion Leung, Hong Kong Polytechnic University, China
Chao Liu, Beihang University, China
Shaoying Liu, Hosei University, Japan
Stephane Maag, Institut Telecom, France
Darko Marinov, University of Illinois, USA
Eliane Martins, Campinas University, Brazil
Wassim Masri, American University of Beirut, Lebanon
Mercedes Merayo, Complutense de Madrid University, Spain
James Miller, University of Alberta, Canada
Aditya Nori, Microsoft, USA
Marcel Oliveira, Federal University of Rio Grande do Norte, Brazil
Alex Orso, Georgia Institute of Technology, USA
Ioannis Parissis, Grenoble Institute of Technology, France
Jan Peleska, University of Bremen, Germany
Alex Petrenko, CRIM, Canada
Jan Philips, Validas AG, Germany
Andrea Polini, University of Camerino, Italy
S. Ramesh, General Motors India Science Lab, India
Filippo Ricca, University of Genoa, Italy
Ismael Rodriguez, Complutense de Madrid University, Spain
Vasile Rus, University of Memphis, USA
Sreedevi Sampath, University of Maryland- Baltimore County, USA
Holger Schlingloff, Fraunhofer FIRST, Germany
K.C. Shashidhar, Fraunhofer IESE, Germany
Avik Sinha, IBM, USA
Saurabh Sinha, IBM Research-India, India
Kari Smolander, Lapprenanta University of Technology, Finland
Mary Lou Soffa, University of Virginia, USA
Nikolai Tillmann, Microsoft, USA
Paolo Tonella, ITC-IRST, Italy
Andreas Ulrich, Siemens, Germany
Margus Veanes, Microsoft, USA
Willem Visser, University of Stellenbosch, South Africa
Stephan Weissleder, Humboldt University of Berlin, Germany
Elaine Weyuker, AT&T, USA
Burkhart Wolff, ParisSud University, France
Tao Xie, North Carolina State University, USA
Baowen Xu, Nanjing University, China
Nina Yevtushenko, Tomsk State University, Russia
Hoijin Yoon, Hyupsung University, Korea
Fatima Zaidi, Paris Sud University, France
Andreas Zeller, Saarland University, Germany